

Search Notes

Application/Control No.

10/726,273

Examiner

Tae H. Yoon

Applicant(s)/Patent under
Reexamination

CZAYKA ET AL.

Art Unit

1714

SEARCHED

Class	Subclass	Date	Examiner
523	500	P-P-06-4	
522	104		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Inventor Search	P-P-06	me